

(12) PATENT APPLICATION PUBLICATION

(21) Application No.202341030895 A

(19) INDIA

(22) Date of filing of Application :29/04/2023

(43) Publication Date : 05/05/2023

(54) Title of the invention : A SYSTEM FOR ENSEMBLE LEARNING WITH CONVOLUTION NEURAL NETWORK FOR AUTOMATIC IDENTIFICATION OF IMPLANT MANUFACTURER USING X-RAY RADIOGRAPHS

(51) International classification :A61B 060000, G06K 096200, G06N 030400, G06N 030800, G06N 202000  
(86) International Application No :PCT//  
Filing Date :01/01/1900  
(87) International Publication No : NA  
(61) Patent of Addition to Application Number :NA  
Filing Date :NA  
(62) Divisional to Application Number :NA  
Filing Date :NA

(71)Name of Applicant :

**1)Dr. B. R. Ambedkar Chair-Andhra University**

Address of Applicant :Andhra University, Visakhapatnam, Andhra Pradesh, India. Pin Code:530003 -----

Name of Applicant : NA

Address of Applicant : NA

(72)Name of Inventor :

**1)Prof. James Stephen Meka**

Address of Applicant :Dr. B. R. Ambedkar Chair Professor, Dean, A.U. TDR-HUB, Andhra University, Visakhapatnam, Andhra Pradesh, India. Pin Code: 530003 -----

**2)Mr.Rajendraprasad Banavathu**

Address of Applicant :Research Scholar, Department of CS & SE, A.U. College of Engineering (A), Andhra University, Visakhapatnam, Andhra Pradesh, India. Pin Code: 530003 -----

**3)Prof. Prasad Reddy P.V.G.D.**

Address of Applicant :Senior Professor, Department of CS & SE, A.U. College of Engineering (A), Andhra University, Visakhapatnam, Andhra Pradesh, India. Pin Code: 530003 -----

(57) Abstract :

[038] The present invention discloses a system for ensemble learning with Convolution Neural Network for automatic identification of implant manufacturer using X-ray radiographs. In the present invention, an ensemble model for automatic implant manufacturer prediction using X-ray radiography. Our model employs multiple convolutional neural networks to achieve a reliable prediction of the implant manufacturer based on x-ray images. The individual CNN variants involved in the implant prediction were trained separately to make independent predictions and then combined using a weighted average ensembling method to predict the manufacturer of the implant. We trained the individual pre-trained model for 150 epochs using the training set and validated the model using the validation set. The performance of the pretrained models were monitored and evaluated based on model accuracy, precision, recall and F1 score. The ensemble model has shown promising performance in terms of the aforementioned evaluation metrics, thus we believe that the model will be a useful tool in preoperative planning and can be applied in the identification and classification of implants from other manufacturers. Accompanied Drawing [FIGS. 1-2]

No. of Pages : 26 No. of Claims : 7